



IFW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Kaoru MATSUKI et al.

Group Art Unit: 2877

Application No.: 10/614,203

Filed: July 8, 2003

Docket No.: 116454

For: SURFACE PROFILE MEASURING INSTRUMENT AND SURFACE PROFILE
MEASURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. The references 1-3 were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully submitted,


James A. Oliff
Registration No. 27,075

Philip A. Caramanica, Jr.
Registration No. 51,528

JAO:PAC/vcj

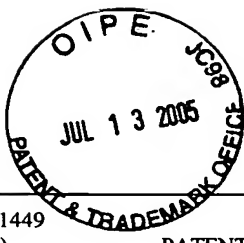
Date: July 13, 2005

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

DEPOSIT ACCOUNT USE
AUTHORIZATION

Please grant any extension
necessary for entry;

Charge any fee due to our
Deposit Account No. 15-0461

Sheet 1 of 1Form PTO-1449
(REV. 8-83)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
116454APPLICATION NO.
10/614,203

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Kaoru MATSUKI et al.FILING DATE
July 8, 2003GROUP
2877

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS |
|---------------------|--|-----------------|------|------|-------|--------------|
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB CLASS |
|--|---|------------------|------------|---------|-------|--------------|
| | 1 | EP 0 858 015 A1 | 08/12/1998 | EUROPE | | |
| | 2 | DE 100 00 250 A1 | 08/31/2000 | GERMANY | | |
| | 3 | DE 100 35 714 A1 | 07/12/2001 | GERMANY | | |
| | | | | | | |
| | | | | | | |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

| | | |
|--|--|--|
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: July 13, 2005